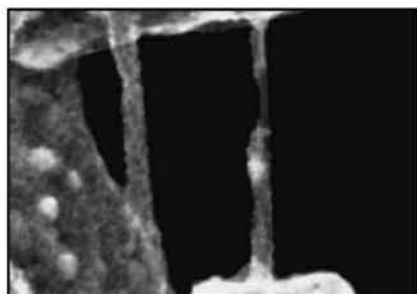


The Ultimate in Resolution.



X1000k, 30.0kV Single Walled Nanotube

The Hitachi S-5500 is a dedicated ultra-high resolution In-lens FE-SEM for leading edge research and development of nanotechnologies.

The patented in-lens technology provides the ultimate performance of 0.5nm guaranteed imaging resolution.

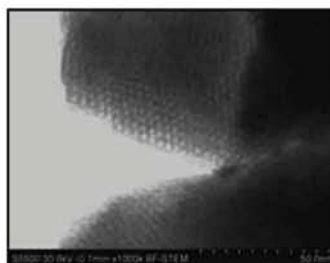
The S-5500 is equipped with a shielding system for reduced EMI and acoustic interferences. These improvements with a completely dry vacuum system ensures Hitachi's high-resolution guarantee for the life of the instrument.

A newly designed BF/DF Duo-STEM detector (patent pending) contains an adjustable dark field detector for tunable collection angles.

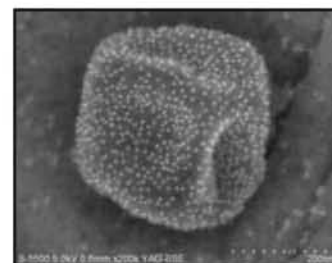
Sometimes a single image can change the way we look at life. The new S-5500 with its advances in information collection will lead you to those opportunities.

Hitachi S-5500

In-lens Field Emission Scanning Electron Microscope



X1000k, 30.0kV Mesoporous Silica



X200k, 5.0kV Immuno Labeling



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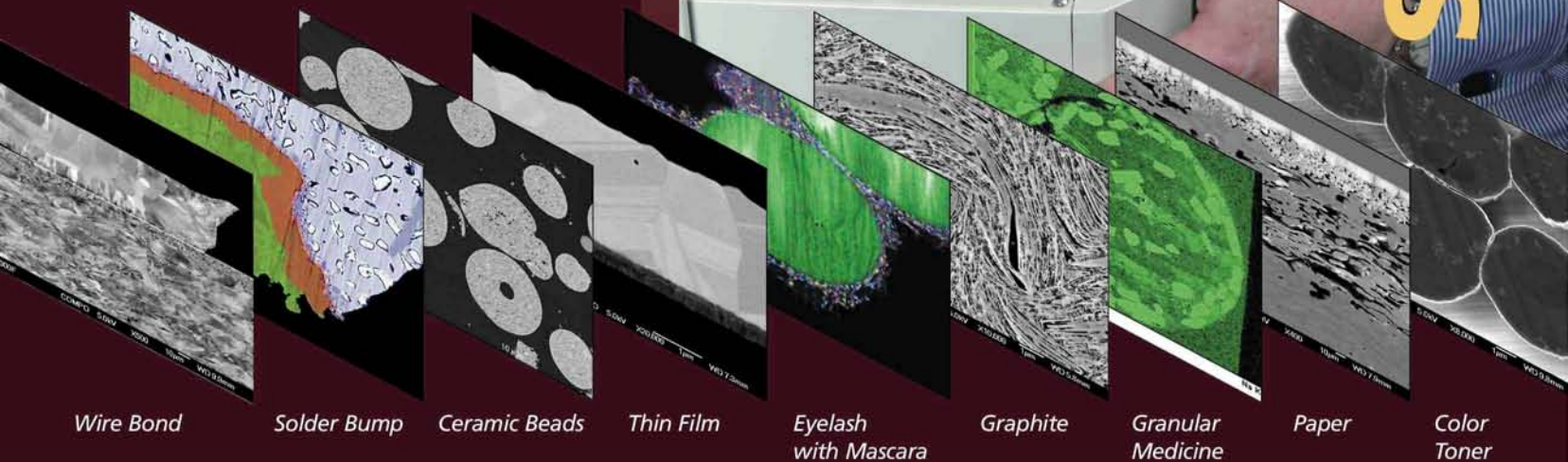
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